9. A surface acoustic wave device comprising:

a quartz substrate;

a piezoelectric thin film disposed on said quartz substrate;

comb electrodes disposed between said quartz substrate and said piezoelectric thin film; and

the normalized film thickness H/λ of said piezoelectric thin film is at least about 0.20, wherein the film thickness of said piezoelectric thin film is H, and the wavelength of a surface acoustic wave is λ; wherein

the Euler angles of said quartz substrate are within the range such that the power flow angle PFA of a Rayleigh wave is within about $\pm$ 2.5°; and

the Euler angles of said quartz substrate are within the range such that the electromechanical coupling coefficient for a spurious wave $K_{sp}{}^2$ is not larger than about 0.1%.

Please cancel claim 2 without prejudice or disclaimer of the subject matter contained therein.

Please add the following new claim 14:

14. A surface acoustic wave device, comprising:

a quartz substrate;

a piezoelectric thin film disposed on said quartz substrate;

comb electrodes disposed between said quartz substrate and said piezoelectric thin film; and

the normalized film thickness H/λ of said piezoelectric thin film is at least about 0.20, wherein the film thickness of said piezoelectric thin film is H, and the wavelength of a surface acoustic wave is λ; wherein

the Euler angles of said quartz substrate are within a range such that the power flow angle PFA of a Rayleigh wave is within about $\pm$ 2.5°;

said range of the Euler angles set such that the PFA is within about $\pm\,2.5°$ is within an area surrounded by lines which are represented by the following equations:

$\theta=201.77292-8.1909*\psi+0.3257*\psi^2-0.00532*\psi^3+0.0000286691*\psi^4$ and $3\leqq\psi\leqq40$;

$\theta=-2.3333*\psi+221.33$ and $40\leqq\psi\leqq43$;

$\theta=-20.667*\psi+1009.7$ and $43\leqq\psi\leqq44.5$;

$\psi=242.92932-2.46296*\theta-0.04285*\theta^2+0.000792121*\theta^3-0.00000316309*\theta^4$ and $60\leqq\psi\leqq106$;

$\theta=60$ and $28\leqq\psi\leqq70$;

$\theta=1.39744*\psi^2-78.37179*\psi+1158.8$ and $27.5\leqq\psi\leqq32$;

$\theta=9.8429+15.55204*\psi-1.0153*\psi^2+0.0306*\psi^3-0.00038175*\psi^4$ and $3\leqq\psi\leqq32$;

$\theta=60$ and $0\leqq\psi\leqq4$;

$\psi=0$ and $60\leqq\theta\leqq180$;

$\theta=180$ and $0\leqq\psi\leqq4$; and

the Euler angles of said quartz substrate are within a range such that the electromechanical coupling coefficient for a spurious wave, K_{sp}^2 is not larger than about 0.05%;

said range of the Euler angles set such that K_{sp}^2 is not larger than about 0.05% is within an area surrounded by lines which are represented by the following equations:

$\theta=461.5-51.23992*\psi+3.55894*\psi^2-0.12153*\psi^3+0.00171*\psi^4$ and $12\leqq\psi\leqq25.5$;
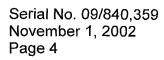
$\theta=-10*\psi+425$ and $24\leqq\psi\leqq25.5$;

$\theta=-88.97104+38.79904*\psi-1.80561*\psi^2+0.03334*\psi^3-0.000217323*\psi^4$ and $27\leqq\psi\leqq43$;

$\theta=-0.013928594*\psi^4+2.255507173*\psi^3-136.803833233*\psi^2+3684.063042727*\psi-37024.00$ and $33\leqq\psi\leqq43$;

$\theta=0.0009461088154*\psi^4-0.178399621211*\psi^3+12.5950972795403*\psi^2-395.999782194768*\psi+4763.57$ and $33\leqq\psi\leqq55$;

θ=60 and $29 \leqq \psi \leqq 55$;

θ=0.01724063*ψ^3-1.20723413*ψ^2+24.63357158*ψ-58 and $16 \leqq \psi \leqq 30$;

θ=0.0139*ψ^2+0.9028*ψ+79 and $79 \leqq \psi \leqq 100$;

ψ=0 and $78 \leqq \theta \leqq 180$;

θ=180 and $0 \leqq \psi \leqq 13$;

θ=180 and $24 \leqq \psi \leqq 29$.